

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MICRON: ~~210A~~APPLICATION NO.
~~18/193,436~~

219C1

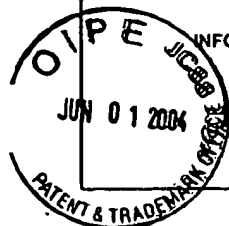
10/760,127

INFORMATION DISCLOSURE STATEMENT
BY APPLICANTAPPLICANT
Katti, et al.FILING DATE
~~July 10, 2002~~

1/16/04

GROUP
~~Unknown~~

2818



SEE SEVERAL SHEETS IF NECESSARY)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TN	Daughton, James M., "Advanced MRAM Concepts" Article from NVE Corporation, February 07, 2001, pp. 1-6

MSO-3284.DOC:afa
073002

BEST AVAILABLE COPY

EXAMINER <i>Anty</i>	DATE CONSIDERED 9/20/2004
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON 219A 219C1	APPLICATION NO. 10/193,468 10/760,127
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Katti, et al.	
		FILING DATE July 10, 2002 1/16/04	GROUP Unknown 2818

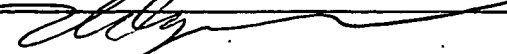
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TTN	"Magnetoelctronics" [online] [retrieved on January 25, 2002] Retrieved from the Internet: <URL: www.lpm.virginia.edu/research/PVD/Pubs/thesis7/chapter2.PDF> Chapter 2 pp. 7-34
TDN	Everitt, et al., "Pseudo Spin Valve MRAM Cells with Sub-Micrometer Critical Dimension" <u>IEEE</u> Transaction on Magnetics, Vol. 34, No. 4, (1998), pp. 1060-1062
TDN	Lee, et al., "Separation of Contributions to Spin Valve Interlayer Exchange Coupling Field by Temperature Dependent Coupling Field Measurements" [online] 46th MMM Conference Seattle, Washington 2001 pp. 1-16 [retrieved on January 25, 2002] Retrieved from the Internet: <URL:www.andrew.cmu.edu/~zlee/mmm.pdf>
TDN	Shi, et al., "End Domain States and Magnetization Reversal in Submicron Magnetic Structures" <u>IEEE</u> Transactions on Magnetics, Vol. 34, No. 4, July 1998, pp. 997-999
TDN	"Non-Volatile Memory (MRAM)" <u>ANXXX</u> [online] Honeywell <retrieved on November 19, 2001> <URL: www.ssec.honeywell.com/avionics/h_gmr.pdf> pp. 1-4

L:\DOCS\MSO\MSO-3453.DOC
090602

BEST AVAILABLE CC

EXAMINER 	DATE CONSIDERED 9/20/2004
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MICRON 218A 219C1	APPLICATION NO. 10/193,458 10/760,127
	APPLICANT Katti, et al.	
	FILING DATE July 10, 2002 1/16/04	GROUP 2818

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
TDM	5,541,868	07/30/96	Prinz				
	6,215,695 B1	04/10/01	Ikeda				

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
						YES	NO	

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TDM	PCT International Search Report dated July 29, 2003
TDM	Inomata, K. "Present and Future of Magnetic RAM Technology" <i>IEICE Transactions on Electronics</i> , Vol. E84-C, No. 6, (June 2001), pp. 740-746

L:\DOCS\MSO\MSO-4624.DOC
082203

BEST AVAILABLE C

EXAMINER	DATE CONSIDERED
<i>[Signature]</i>	9/20/2004
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 809; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

Notice of References Cited	Application/Control No. 10/493,458 - 10/760,127	Applicant(s)/Patent Under Reexamination KATTI ET AL.	
	Examiner Thanh T. Nguyen <i>Unknown</i>	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,627,703 ✓	05-1997	Smith, Neil	360/314
	B	US-6,452,764 ✓	09-2002	Abraham et al.	360/324.2
	C	US-2002/0018323 ✓	02-2002	Li et al.	360/314
	D	US-2003/0007398 ✓	01-2003	Daughton et al.	365/200
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS


*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	BEST AVAILABLE
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office
 PTO-892 (Rev. 01-2001)

Notice of References Cited

Part of Paper No. 3


 Examiner

Pat.
 9/20/2004